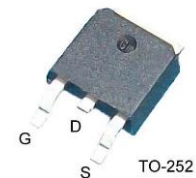




BCD100N16

**Silicon N-Channel MOSFET****Features**

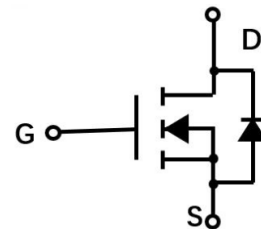
- 100V, 50A
- $R_{DS(ON)} = 16.5m\Omega$  (Max.) @  $V_{GS} = 10V$ ,  $I_D = 20A$
- Low  $R_{DS(on)}$  & FOM
- Extremely low switching loss
- Excellent stability and uniformity
- 100% UIS tested , 100%  $\Delta V_{DS}$  Tested
- RoHS and Halogen-Free Compliant

**Package**

BCD100N16

**Application**

- High Frequency Switching
- Synchronous Rectification

**Absolute Maximum Ratings**  $T_C=25^\circ\text{C}$  unless otherwise specified

Symbol	Parameter		Max.	Units
$V_{DSS}$	Drain-Source Voltage		100	V
$V_{GSS}$	Gate-Source Voltage		$\pm 20$	V
$I_D$	Continuous Drain Current <sup>note5</sup>	$T_C = 25^\circ\text{C}$	50	A
$I_D$	Continuous Drain Current <sup>note5</sup>	$T_C = 100^\circ\text{C}$	31.5	A
$I_{DM}$	Pulsed Drain Current <sup>note3</sup>		200	A
$P_D$	Power Dissipation <sup>note2</sup>	$T_C = 25^\circ\text{C}$	68	W
$I_{AS}$	Avalanche Current <sup>note3,6</sup>		8	A
$E_{AS}$	Single Pulse Avalanche Energy <sup>note3,6</sup>		32	mJ
$R_{\theta JC}$	Thermal Resistance, Junction to Case		1.85	$^\circ\text{C/W}$
$R_{\theta JA}$	Thermal Resistance, Junction to Ambient <sup>note1,4</sup>		55	$^\circ\text{C/W}$
$T_J, T_{STG}$	Operating and Storage Temperature Range		-55 to +150	$^\circ\text{C}$

## Electrical Characteristics $T_C=25^{\circ}\text{C}$ unless otherwise specified

Symbol	Parameter	Test Condition	Min.	Typ.	Max.	Units
Off Characteristic						
BV <sub>DSS</sub>	Drain-Source Breakdown Voltage	V <sub>GS</sub> = 0V, I <sub>D</sub> = 250μA	100	-	-	V
I <sub>DSS</sub>	Drain-Source Leakage Current	V <sub>DS</sub> = 80V, V <sub>GS</sub> = 0V	-	-	1	μA
I <sub>GSS</sub>	Gate to Body Leakage Current	V <sub>DS</sub> = 0V, V <sub>GS</sub> = ±20V	-	-	±100	nA
On Characteristics						
V <sub>GS(th)</sub>	Gate Threshold Voltage	V <sub>DS</sub> = V <sub>GS</sub> , I <sub>D</sub> = 250μA	1.2	1.8	2.5	V
R <sub>DS(on)</sub>	Static Drain-Source On-Resistance	V <sub>GS</sub> = 10V, I <sub>D</sub> = 20A	-	14.6	16.5	mΩ
		V <sub>GS</sub> = 4.5V, I <sub>D</sub> = 10A	-	19.5	23.5	mΩ
R <sub>g</sub>	Gate Resistance	V <sub>DS</sub> = V <sub>GS</sub> =0V, f = 1.0MHz	-	1.44	-	Ω
Dynamic Characteristics						
C <sub>iss</sub>	Input Capacitance	V <sub>DS</sub> = 25V, V <sub>GS</sub> = 0V, f = 1.0MHz	-	1130	-	pF
C <sub>oss</sub>	Output Capacitance		-	496	-	pF
C <sub>rss</sub>	Reverse Transfer Capacitance		-	60	-	pF
Switching Characteristics						
Q <sub>g</sub>	Total Gate Charge	V <sub>DS</sub> = 50V, I <sub>D</sub> = 40A, V <sub>GS</sub> = 10V	-	30	-	nC
Q <sub>gs</sub>	Gate-Source Charge		-	6	-	
Q <sub>gd</sub>	Gate-Drain(“Miller”) Charge		-	8.2	-	
t <sub>d(on)</sub>	Turn-On Delay Time	V <sub>DS</sub> = 50V, I <sub>D</sub> = 40A, R <sub>G</sub> = 3.3Ω, V <sub>GS</sub> =10V	-	46	-	ns
t <sub>r</sub>	Turn-On Rise Time		-	55	-	
t <sub>d(off)</sub>	Turn-Off Delay Time		-	249	-	
t <sub>f</sub>	Turn-Off Fall Time		-	105	-	
Diode Characteristics						
I <sub>S</sub>	Continuous Source Current		-	-	50	A
V <sub>SD</sub>	Diode Forward Voltage	I <sub>S</sub> =20A . V <sub>GS</sub> = 0V	-	0.88	1.0	V
t <sub>rr</sub>	Reverse Recovery Time	I <sub>SD</sub> =20A,	-	70	-	ns
Q <sub>rr</sub>	Reverse Recovery Charge	dI <sub>SD</sub> /dt=100A/μs	-	224	-	nC

### Notes:

1. The value of  $R_{\theta JC}$  is measured in a still air environment with  $T_A = 25^{\circ}\text{C}$  and the maximum allowed junction temperature of  $150^{\circ}\text{C}$ . The value in any given application depends on the user's specific board design.
2. The power dissipation  $P_D$  is based on  $T_{J(MAX)}=150^{\circ}\text{C}$ , using junction-to-case thermal resistance, and is more useful in setting the upper dissipation limit for cases where additional heatsinking is used.
3. Single pulse width limited by junction temperature  $T_{J(MAX)}=150^{\circ}\text{C}$ .
4. The  $R_{\theta JA}$  is the sum of the thermal impedance from junction to case  $R_{\theta JC}$  and case to ambient.
5. The maximum current rating is package limited.
6. The EAS data shows Max. rating. The test condition is  $V_{DS}=50V, V_{GS}=10V, L=0.5mH$

## Typical Performance Characteristics

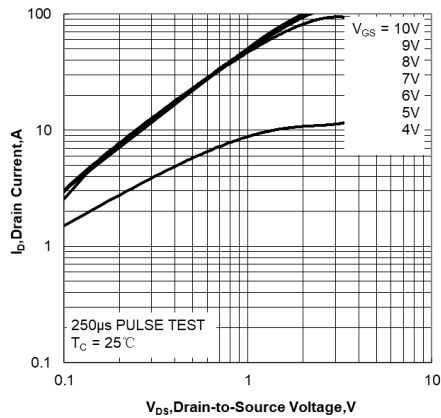


Figure 1. Output Characteristics

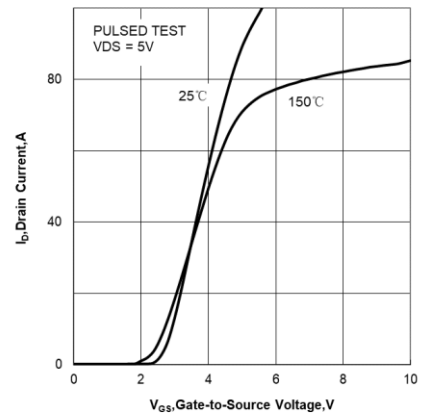


Figure 2. Transfer Characteristics

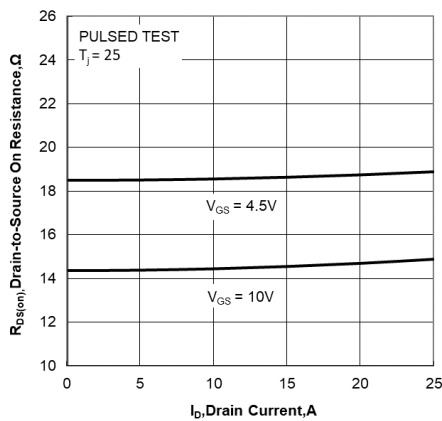


Figure 3. Drain-to-Source On Resistance vs Drain Current

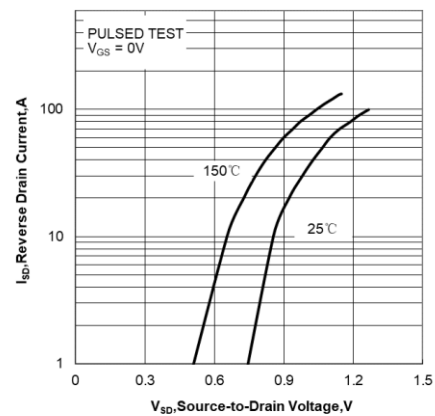


Figure 4. Body Diode Forward Voltage vs Source Current and Temperature

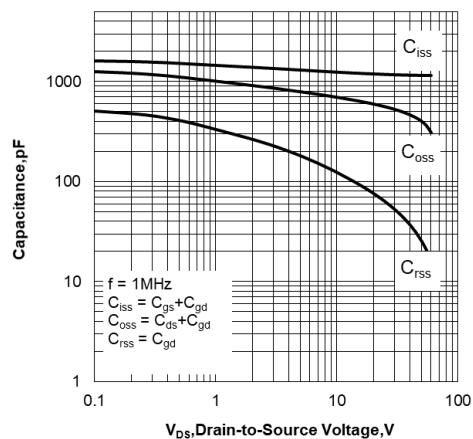


Figure 5. Capacitance Characteristics

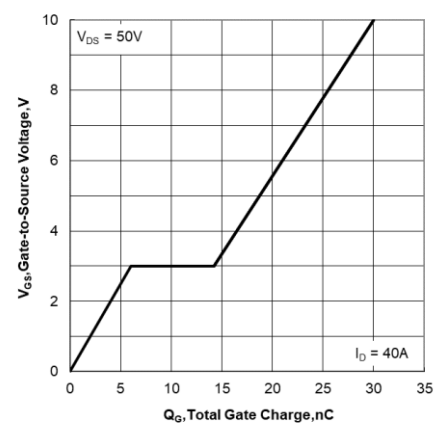
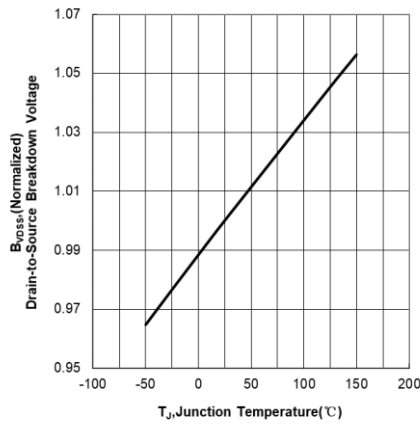
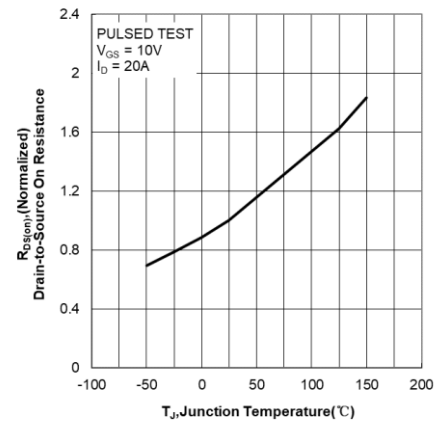


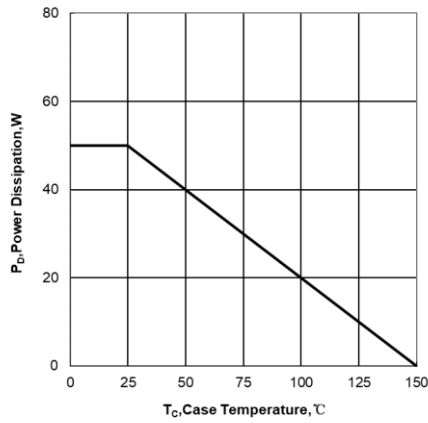
Figure 6. Gate Charge Characteristics



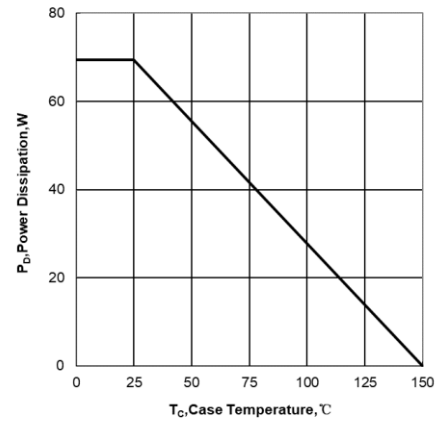
**Figure 7. Normalized Breakdown Voltage vs Junction Temperature**



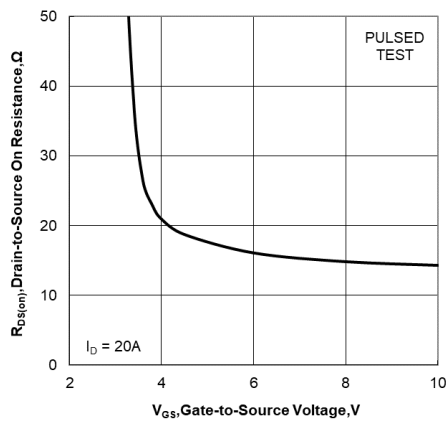
**Figure 8. Normalized On Resistance vs Junction Temperature**



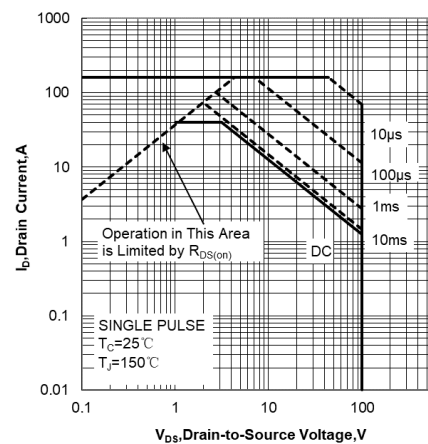
**Figure 9. Maximum Continuous Drain Current vs Case Temperature**



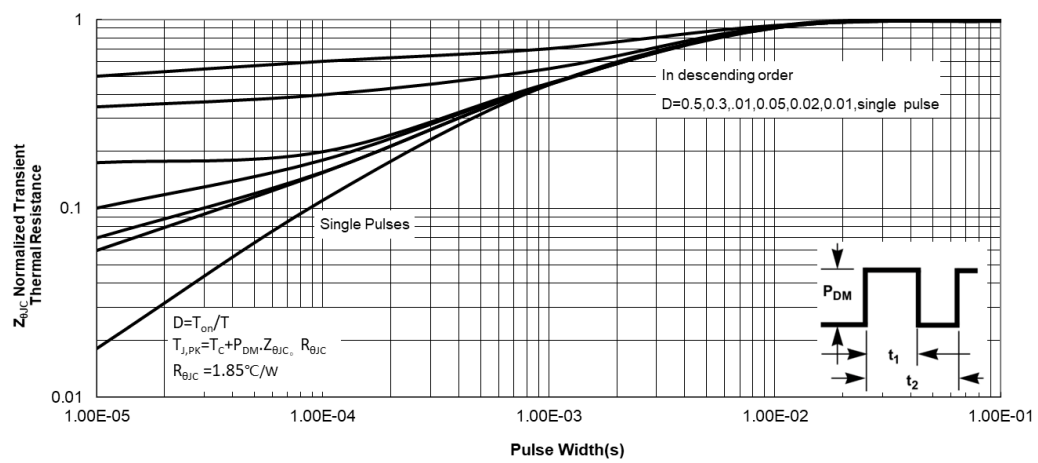
**Figure 10. Maximum Power Dissipation vs Case Temperature**



**Figure 11. Drain-to-Source On Resistance vs Gate Voltage and Drain Current**

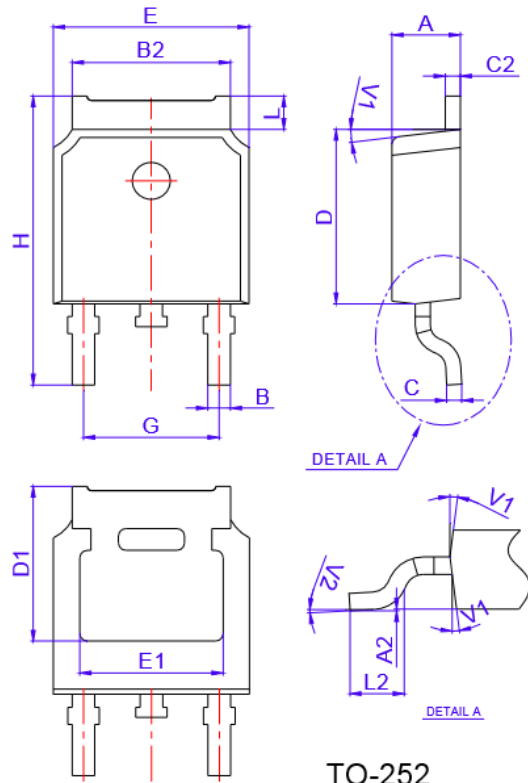


**Figure 12. Maximum Safe Operating Area**



**Figure 13. Maximum Effective Transient Thermal Impedance, Junction-to-Case**

## TO-252 Package Mechanical Data



Ref.	Dimensions					
	Millimeters			Inches		
	Min.	Typ.	Max.	Min.	Typ.	Max.
A	2.10		2.50	0.083		0.098
A2	0		0.10	0		0.004
B	0.66		0.86	0.026		0.034
B2	5.18		5.48	0.202		0.216
C	0.40		0.60	0.016		0.024
C2	0.44		0.58	0.017		0.023
D	5.90		6.30	0.232		0.248
D1	5.30REF			0.209REF		
E	6.40		6.80	0.252		0.268
E1	4.63			0.182		
G	4.47		4.67	0.176		0.184
H	9.50		10.70	0.374		0.421
L	1.09		1.21	0.043		0.048
L2	1.35		1.65	0.053		0.065
V1		7°			7°	
V2	0°		6°	0°		6°